Electronic Supplementary Material (ESI) for Journal of Materials Chemistry A.

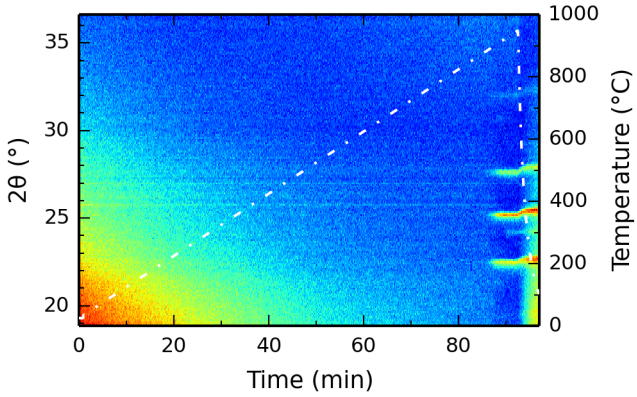

Figure S1: In-situ XRD during annealing of a 90 nm titanium phosphate film in an air atmosphere. The diffracted intensity is represented by color intensity as a function of the diffraction angle on the left y-axis and the elapsed time on the x-axis. The temperature profile is drawn by the white dashed line, using the temperature scale on the right y-axis.

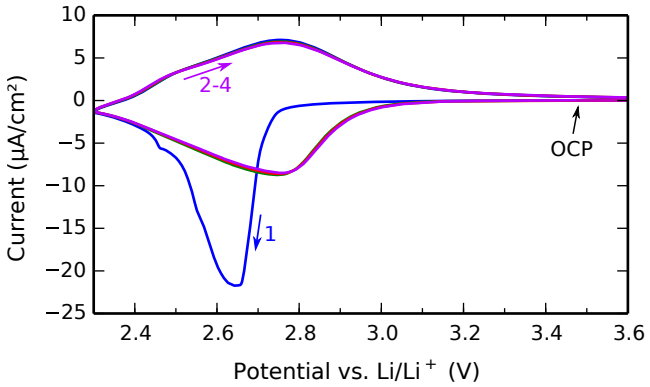

Figure S2: Cyclic voltammogram showing the initial lithiation of a 30 nm as-deposited titanium phosphate film. The potential was swept linearly from the open-circuit potential (OCP) to 2.3 V, and then cycled between 2.3 V and 3.6 V at a scan rate of 1 mV/s. Scan numbers are indicated.